

Title (en)

METHOD AND APPARATUS FOR DETECTING DENSITY AND/OR THICKNESS VARIATIONS IN MATERIALS TRANSPARENT OR PARTLY TRANSPARENT TO INFRARED RADIATION

Title (de)

VERFAHREN UND VORRICHTUNG ZUR ERKENNUNG VON DICHT- UND/ODER DICKENUNTERSCHIEDEN FÜR INFRAROTSTRAHLUNG TRANSPARENTEN ODER TEILTRANSPARENTEN MATERIALIEN

Title (fr)

PROCÉDÉ ET DISPOSITIF DE RECONNAISSANCE DE DIFFÉRENCES DE DENSITÉ ET/OU D'ÉPAISSEUR, POUR DES MATÉRIAUX TRANSPARENTS OU PARTIELLEMENT TRANSPARENTS AU RAYONNEMENT INFRAROUGE

Publication

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Application

**EP 09725225 A 20090130**

Priority

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Abstract (en)

[origin: WO2009118074A1] The invention relates to a method and an apparatus for detecting density and/or thickness variations in materials transparent or partly transparent to infrared radiation, in which an examination object (1, 10) is arranged between an infrared source (3) and a thermographic camera (2), the examination object (1, 10) being irradiated by the infrared source (3) and the thermographic camera (2) arranged opposite the infrared source (3) detecting and evaluating the infrared beams from the infrared source (3) passing through the examination object (1, 10).

IPC 8 full level

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CPC (source: EP US)

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Citation (search report)

See references of WO 2009118074A1

Citation (examination)

- US 2002122172 A1 20020905 - ROSS DENWOOD F [US], et al
- DE 19846995 A1 20000504 - FRAUNHOFER GES FORSCHUNG [DE]

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